

L Number	Hits	Search Text	DB	Time stamp
1	2465	((349/73) or (349/74) or (349/113) or (349/187)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 12:22
2	107	lcmd	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 12:22
3	53	lcmd and @py<2000	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 12:23
-	2	"6330099"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 13:26
-	2	"6362861"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:29
-	2231	"Agilent Technologies".AS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:36
-	0	"Agilent Technologies".AS. and 349/190	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:37
-	0	"anistropic etch" adj "filling hole"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:46
-	0	"anistropic etch" adj "liquid crystal filling hole"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:47
-	0	"anistropic etch" adj "liquid crystal"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 10:48
-	153	(349/190).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:20
-	440	(438/30).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 12:46

	1	"anisotropic etch" adj "silicon wafer"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 12:55
	3	"anisotropic etch" near "silicon wafer"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 12:56
	61	"anisotropic etching" adj "silicon wafer"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:14
	0	"anisotropic etching" near "liquid crystal"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:15
	0	"anisotropic etching" near "liquid crystal substrate"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:15
	708	"anisotropic etching" near "substrate"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:23
	144	(349/154).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:26
	10	"injection hole" adj "substrate"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 18:05
	0	"sealant" adj "glue, epoxy, solder"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:46
	0	"sealant material" adj "glue, epoxy, and solder"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:46
	311	"sealant" adj "epoxy"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 13:54
	3	"liquid crystal" adj "microdisplays"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 14:22
	83	"testing" adj "liquid crystal display"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 14:29

	0	"testing" adj "liquid crystal micro display"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 14:27
	0	"testing" adj "sealing hole"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 14:29
	0	"testing" adj " liquid crystal sealing hole"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 14:30
	2	"6330099"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:09
	0	(349/190 and testing).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:18
	0	349/190 adj testing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:18
	0	349/190 near testing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:18
	0	"349/190" near "testing"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:18
	0	"349/190" adj "testing"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:18
	475	(438/15).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 15:21
	98	(injection hole) adj (glue)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 16:19
	32	"sealant material" adj "epoxy"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 16:30
	0	"liquid crystal" adj "sealant material" adj "epoxy"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 16:30

	0	"liquid crystal" adj "sealant material"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 16:31
	3	"liquid crystal" near "sealant material"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 16:31
	7	"6177288"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/02 18:05
	21	(liquid adj crystal) near10 (micro adj displays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 13:35
	4	liquid adj crystal adj micro-displays	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 13:36
	7	liquid adj crystal adj micro adj displays	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 13:37
	1078	(plurality adj holes) near10 substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 13:40
	129	(liquid adj crystal) near10 (injection adj holes)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:34
	0	((liquid adj crystal) near10 (micro adj displays)) and (liquid adj crystal adj micro-displays) and (liquid adj crystal adj micro adj displays) and ((liquid adj crystal) near10 (injection adj holes))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 14:39
	4	((liquid adj crystal) near10 (micro adj displays)) and (liquid adj crystal adj micro-displays) and (liquid adj crystal adj micro adj displays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 14:40
	0	((liquid adj crystal) near10 (micro adj displays)) and ((liquid adj crystal) near10 (injection adj holes))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 14:50
	7	"6177288"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 16:03
	0	(seal) near10 (glue and epoxy and solder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:37

	9392	(semiconductor adj substrate) near10 (integrated adj circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:42
	1767	(semiconductor adj substrate) near10 (silicon adj wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:44
	3221	(semiconductor adj substrate) near10 (glass)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:47
	7	((semiconductor adj substrate) near10 (integrated adj circuit)) and ((semiconductor adj substrate) near10 (silicon adj wafer)) and ((semiconductor adj substrate) near10 (glass))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:54
	2	6445436.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:55
	0	(micro adj display) near10 (uniform adj image)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:57
	3	(liquid adj crystal adj displays) near10 (uniform adj image)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 15:58
	0	"6177288.did."	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 16:03
	2	6177288.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 16:03
	3	sojourner-douglas.IN. and (micro adj displays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/03 09:34
	5875	micro near10 display	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:08
	30228	349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:09
	379	(micro near10 display) and 349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:10

	0	(micro near10 display) near10 349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:11
	477	(manufacturing or making or method) near10 (micro near10 display)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:12
	49	((manufacturing or making or method) near10 (micro near10 display)) and 349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/30 14:12
	2	6562640.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:17
	6276	((micro near10 display) or microdisplay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:30
	312132	liquid near10 crystal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:33
	202	(making or manufatur\$3) near10 (liquid near10 crystal) near10 (((micro near10 display) or microdisplay))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:36
	319670	semiconductor near10 substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:39
	388883	integrated near10 circuit	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:42
	70818	silicon near10 wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:45
	382	(semiconductor near10 substrate) near10 (integrated near10 circuit) near10 (silicon near10 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:48
	0	((making or manufatur\$3) near10 (liquid near10 crystal) near10 (((micro near10 display) or microdisplay))) near10 ((semiconductor near10 substrate) near10 (integrated near10 circuit) near10 (silicon near10 wafer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:48
	2	((making or manufatur\$3) near10 (liquid near10 crystal) near10 (((micro near10 display) or microdisplay))) and ((semiconductor near10 substrate) near10 (integrated near10 circuit) near10 (silicon near10 wafer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:49

	10929	(semiconductor near10 substrate) and (integrated near10 circuit) and (silicon near10 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:51
	382	((semiconductor near10 substrate) near10 (integrated near10 circuit) near10 (silicon near10 wafer)) and ((semiconductor near10 substrate) and (integrated near10 circuit) and (silicon near10 wafer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:52
	30494	349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:53
	3	((semiconductor near10 substrate) near10 (integrated near10 circuit) near10 (silicon near10 wafer)) and ((semiconductor near10 substrate) and (integrated near10 circuit) and (silicon near10 wafer))) and 349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:54
	2	"6562640"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 10:55
	571	(438/15).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 12:43
	2	438/15 and (microdisplay or (micro near10 display))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 12:43
	2	6177288.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:27
	194	testing near10 after near10 sealing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:30
	30494	349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:31
	2	(testing near10 after near10 sealing) and 349\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:39
	6276	(micro near10 display) or microdisplay	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:40
	0	testing near10 ((micro near10 display) or microdisplay) near10 after near10 sealing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:41

	1	testing near10 ((micro near10 display) or microdisplay) near10 sealing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:42
	0	sealing near10 before near10 testing near10 ((micro near10 display) or microdisplay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/04 13:42
	712	"micro display" or "microdisplay"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:31
	336289	liquid near6 crystal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:34
	166	(liquid near6 crystal) near6 ("micro display" or "microdisplay")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:46
	18	((liquid near6 crystal) near6 ("micro display" or "microdisplay")) and @py<2000	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:34
	1	349/189 and ((liquid near6 crystal) near6 ("micro display" or "microdisplay"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:47
	1	438/15 and ((liquid near6 crystal) near6 ("micro display" or "microdisplay"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:47
	1	438/28 and ((liquid near6 crystal) near6 ("micro display" or "microdisplay"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:48
	929	((349/189) or (438/15) or (438/28)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:50
	430	((349/189) or (438/15) or (438/28)).CCLS.) and @py<2000	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:50
	0	((((349/189) or (438/15) or (438/28)).CCLS.) and @py<2000) and ("micro display" or "microdisplay")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:50
	0	((((349/189) or (438/15) or (438/28)).CCLS.) and @py<2000) and (micro near6 display)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:54

-	120	("micro display" or "microdisplay") and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:54
-	46	(("micro display" or "microdisplay") and wafer) and fill	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:54
-	46	((("micro display" or "microdisplay") and wafer) and fill) and not@ad>20000701	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/21 11:55